

5V Precision Data Acquisition Subsystems

Features

- Precision (up to 17-Bits) A/D Converter
- 3-Wire Serial Port
- Flexible: User Can Trade Off Conversion Speed For Resolution
- Single Supply Operation
- -5V Output Pin
- 4 Input, Differential Analog MUX (TC534)
- Automatic Input Polarity and Overrange Detection
- Low Operating Current: 5mA Max
- Wide Analog Input Range: ±4.2V Max
- Cost Effective
- **Applications**
- Precision Analog Signal Processor
- Precision Sensor Interface
- High Accuracy DC Measurements

Device Selection Table

General Description

The TC530/TC534 are serial analog data acquisition subsystems ideal for high precision measurements (up to 17-bits plus sign). The TC530 consists of a dual slope integrating A/D converter, negative power supply generator and 3 wire serial interface port. The TC534 is identical to the TC530, but adds a four channel differential input multiplexer. Key A/D converter operating parameters (Auto Zero and Integration time) are programmable, allowing the user to trade conversion time for resolution.

Data conversion is initiated when the RESET input is brought low. After conversion, data is loaded into the output shift register and EOC is asserted, indicating new data is available. The converted data (plus Overrange and polarity bits) is held in the output shift register until read by the processor or until the next conversion is completed, allowing the user to access data at any time.

The TC530/TC534 timebase can be derived from an external crystal of 2MHz (max) or from an external frequency source. The TC530/TC534 requires a single 5V power supply and features a -5V, 10mA output which can be used to supply negative bias to other components in the system.

Typical Application

1.0 ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings*

PQFP Package (C) 0°C to +70°C

Storage Temperature Range.............. -65°C to +150°C

*Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operation sections of the specifications is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

TC530/TC530A/TC534 ELECTRICAL SPECIFICATIONS

Note 1: Integrate time ≥ 66msec, Auto Zero time ≥ 66msec, V_{INT} (pk) = 4V.

2: End point linearity at ±1/4, ±1/2 ±3/4, F.S. after full scale adjustment.

3: Rollover error is related to capacitor used for C_{INT}. See Table 5-2, Recommended Capacitor for C_{INT}.

4: TC534 Only.

TC530/TC530A/TC534 ELECTRICAL SPECIFICATIONS (CONTINUED)

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2: End point linearity at ±1/4, ±1/2 ±3/4, F.S. after full scale adjustment.

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4: TC534 Only.

2.0 PIN DESCRIPTIONS

The descriptions of the pins are listed in Table 2-1

TABLE 2-1: PIN FUNCTION TABLE (CONTINUED)

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3.0 DETAILED DESCRIPTION

3.1 Dual Slope Integrating Converter

The TC530/TC534 dual slope converter operates by integrating the input signal for a fixed time period, then applying an opposite polarity reference voltage while timing the period (counting clocks pulses) for the integrator output to cross 0V (deintegrating). The resulting count is read as conversion data.

A simple mathematical expression that describes dual slope conversion is:

EQUATION 3-1:

Integrate Voltage = De-integrate Voltage

EQUATION 3-2:

from which:

EQUATION 3-3:

And therefore:

EQUATION 3-4:

Inspection of Equation 3-4 shows dual slope converter accuracy is unrelated to integrating resistor and capacitor values, as long as they are stable throughout the measurement cycle. This measurement technique is inherently ratiometric (i.e., the ratio between the T_{INT} and T_{DEINT} times is equal to the ratio between V_{IN} and V_{RFF}).

Another inherent benefit is noise immunity. Input noise spikes are integrated, or averaged to zero, during the integration period. The integrating converter has a noise immunity with an attenuation rate of at least -20dB per decade. Interference signals with frequencies at integral multiples of the integration period are, for the most part, completely removed. For this reason, the integration period of the converter is often established to reject 50/ 60Hz line noise. The ability to reject such noise is shown by the plot of Figure 3-1.

In addition to the two phases required for dual slope measurement (Integrate and De-integrate), the TC530/ TC534 performs two additional adjustments to minimize measurement error due to system offset voltages. The resulting four internal operations (conversion phases) performed each measurement cycle are: Auto Zero (AZ), Integrator Output Zero (IZ), Input Integrate (INT) and Reference De-integrate (DINT). The AZ and IZ phases compensate for system offset errors and the INT and DINT phases perform the actual A/D conversion.

FIGURE 3-1: INTEGRATING CONVERTER NORMAL MODE REJECTION

3.2 Auto Zero Phase (AZ)

This phase compensates for errors due to buffer, integrator and comparator offset voltages. During this phase, an internal feedback loop forces a compensating error voltage on auto zero capacitor (C_{AZ}) . The duration of the AZ phase is programmable via the serial port (see Section 4.1.1, AZ and INT Phase Duration).

FIGURE 3-3: A/D CONVERTER TIMING

3.3 Input Integrate Phase (INT)

In this phase, a current directly proportional to differential input voltage is sourced into integrating capacitor C_{INT} . The amount of voltage stored on C_{INT} at the end of the INT phase is directly proportional to the applied differential input voltage. Input signal polarity (sign bit) is determined at the end of this phase. Converter resolution and speed is a function of the duration of the INT phase, which is programmable by the user via the serial port (see Section 4.1.1, AZ and INT Phase Duration). The shorter the integration time, the faster the

speed of conversion (but the lower the resolution). Conversely, the longer the integration time, the greater the resolution (but at slower the speed of conversion).

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3.4 Reference De-integrate Phase (DINT)

This phase consists of measuring the time for the integrator output to return (at a rate determined by the external reference voltage) from its initial voltage to 0V. The resulting timer data is stored in the output shift register as converted analog data.

3.5 Integrator Output Zero Phase (IZ)

This phase ensures the integrator output is at zero volts when the AZ phase is entered so that only true system offset voltages will be compensated for.

All internal converter timing is derived from the frequency source at OSC_{IN} and $\mathrm{OSC}_{\text{OUT}}$. This frequency source must be either an externally provided clock signal or an external crystal. If an external clock is used, it must be connected to the OSC_{IN} pin and the $\mathrm{OSC}_{\mathrm{OUT}}$ pin must remain floating. If a crystal is used, it must be connected between OSC_{IN} and $\mathrm{OSC}_{\text{OUT}}$ and be physically located as close to the OSC_{IN} and OSC_{OUT} pins as possible. In either case, the incoming clock frequency is divided by four, with the resulting clock serving as the internal TC530/TC534 timebase.

4.0 TYPICAL APPLICATIONS

4.1 Programming the TC530/TC534

4.1.1 AZ AND INT PHASE DURATION

These two phases have equal duration determined by the crystal (or external) frequency and the timer initialization byte (LOAD VALUE). Timing is selected as follows:

1. Select Integration Time

Integration time must be picked as a multiple of the period of the line frequency. For example, T_{INT} times of 33msec, 66msec and 132msec maximize 60Hz line rejection.

2. Estimate Crystal Frequency

Crystal frequencies as high as 2MHz are allowed. Crystal frequency is estimated using:

EQUATION 4-1:

 $2(R)/T_{INT}$

where:

- R = Desired Converter Resolution (in counts)
- F_{IN} = Input Frequency (in MHz)
- INT = Integration Time (in seconds)

3. Calculate LOAD VALUE

EQUATION 4-2:

[LOAD VALUE]10 =
$$
\frac{256 \cdot (T_{INT})(F_{IN})}{1024}
$$

 F_{IN} can be adjusted to a standard value during this step. The resulting base, -10 LOAD VALUE, must be converted to a hexadecimal number and then loaded into the serial port prior to initiating A/D conversion.

4.2 DINT and IZ Phase Timing

The duration of the DINT phase is a function of the amount of voltage stored on the integrator capacitor during INT and the value of V_{REF} . The DINT phase is initiated immediately following INT and terminated when an integrator output zero crossing is detected. In general, the maximum number of counts chosen for DINT is twice that of INT (with V_{RFF} chosen at $V_{IN(MAX)}/2$).

4.3 System RESET

The TC530/TC534 must be forced into the AZ state when power is first applied. A .01uF capacitor connected from RESET to V_{DD} (or external system reset logic signal) can be used to momentarily drive RESET high for a minimum of 100msec.

4.4 Design Example

Figure 4-1 shows a typical TC534 interrupt-driven application. Timing and component values are calculated from equations and recommendations made in Section 3.1 and Section 4.1 of this document. The EOC connection to the processor INT input is for interrupt-driven applications only. (In polled systems, the \overline{EOC} output is available on $D_{\Omega UT}$).

Given:

Required resolution:16-bits (65,536 counts.)

Maximum: V_{IN} ±2V

Power supply voltage: +5V

60hz system

- 1. Pick Integration time (T_{INT}) : 66msec
- 2. Estimate crystal frequency.

EXAMPLE 4-1:

 $F_{IN} = 2R/T_{INT} = 2 \times 65536/66 \times 10^{-3} = 1.98 MHz$ (use 2MHz)

3. Calculate LOAD VALUE

EXAMPLE 4-2:

LOAD VALUE = $256 - (T_{INT})(F_{IN})/1024 = [128]_{10}$ $[128]_{10} = 80$ hex

4. Calculate R_{INT}

EXAMPLE 4-3:

 $R_{INT} = V_{INMAX}/20 = 2/20 = 100k\Omega$

5. Calculate C_{INT} for maximum (4V) integrator output swing:

EXAMPLE 4-4:

 $C_{\text{INT}} = (T_{\text{INT}})(20 \times 10^{-6})/(V_{\text{S}} - 0.9)$

 $= (.066)(20 \times 10^{-6})/(4.1)$

 $= .32 \mu$ F (use closest value: 0.33μ F)

- **Note:** Microchip recommended capacitor: Evox-Rifa p/n: SMR5 334K50J03L
- 6. Choose C_{REF} and C_{AZ} based on conversion rate:

EXAMPLE 4-5:

Conversions/sec = $1/(T_{AZ} + T_{INT} + 2T_{INT} + 2msec)$ = 1/(66msec + 66msec + 132msec + 2msec)

= 3.7 conversions/sec

from which $C_{AZ} = C_{RFF} = 0.22 \mu F$ (Table 5-1)

- **Note:** Microchip recommended capacitor: Evox-Rifa p/n: SMR5 224K50J02L4
- 7. Calculate V_{RFF} .

EXAMPLE 4-6:

 $V_{REF} = \frac{(V_S - 0.9)(C_{INT})(R_{INT})}{(C_{INT})}$ 2(T_{INT}) $= (4.1) (0.33 \times 1^{-6}) (10^5) / 2(.066)$ $= 1.025V$

4.5 Power Supply Sequencing

Improper sequencing of the power supply inputs $(V_{DD}$ vs. V_{CCD}) can potentially cause an improper power-up sequence to occur. See Section 4.6, Circuit Design/ Layout Considerations. Failing to insure a proper power-up sequence can cause spurious operation.

4.6 Circuit Design/Layout Considerations

- 1. Separate ground return paths should be used for the analog and digital circuitry. Use of ground planes and trace fill on analog circuit sections is highly recommended EXCEPT for in and around the integrator section and C_{REF} , C_{AZ} (C_{INT}, C_{REF} , C_{AZ} , R_{INT}). Stray capacitance between these nodes and ground appears in parallel with the components themselves and can affect measurement accuracy.
- 2. Improper sequencing of the power supply inputs (V_{DD} vs. V_{CCD}) can potentially cause an improper power-up sequence to occur in the internal state machines. It is recommended that the digital supply, V_{CCD} , be powered up first. One method of insuring the correct power-up sequence is to delay the analog supply using a series resistor and a capacitor. See Figure 4-1, TC530/TC534 Typical Application.
- Decoupling capacitors, preferably a higher value electrolytic or tantulum in parallel with a small ceramic or tantalum, should be used liberally. This includes bypassing the supply connections of all active components and the voltage reference.
- 4. Critical components should be chosen for stability and low noise. The use of a metal-film resistor for R_{INT} and Polypropylene or Polyphenelyne Sulfide (PPS) capacitors for C_{INT} , C_{A7} and C_{RFF} is highly recommended.
- 5. The inputs and integrator section are very high impedance nodes. Leakage to or from these critical nodes can contribute measurement error. A guard-ring should be used to protect the integrator section from stray leakage.
- 6. Circuit assemblies should be exceptionally clean to prevent the presence of contamination from assembly, handling or the cleaning itself. Minute conductive trace contaminates, easily ignored in most applications, can adversely affect the performance of high impedance circuits. The input and integrator sections should be made as compact and close to the TC53X as possible.
- 7. Digital and other dynamic signal conductors should be kept as far from the TC53X's analog section as possible. The microcontroller or other host logic should be kept quiet during a measurement cycle. Background activities such as keypad scanning, display refreshing and power switching can introduce noise.

5.0 SELECTING COMPONENT VALUES FOR THE TC530/TC534

1. Calculate Integrating Resistor (R_{INT})

The desired full scale input voltage and amplifier output current capability determine the value of R_{INT} . The buffer and integrator amplifiers each have a full scale current of 20 μ A. The value of R_{INT} is therefore directly calculated as follows:

EQUATION 5-1:

VINMAX $R_{INT} = \frac{V_{INMAX}}{20}$ m Ω

where:

 $V_{IN(MAX)} =$ Maximum Input Voltage (full count voltage)

 R_{INT} = Integrating Resistor (in mΩ)

For loop stability, R_{INT} should be \geq 50k Ω .

2. Select Reference (C_{REF}) and Auto Zero (C_{AZ}) **Capacitors**

 C_{RFF} and C_{A7} must be low leakage capacitors (such as polypropylene). The slower the conversion rate, the larger the value C_{REF} must be. Recommended capacitors for C_{REF} and C_{AZ} are shown in Table 5-1. Larger values for C_{AZ} and C_{REF} may also be used to limit rollover errors.

TABLE 5-1: CREF AND CAZ SELECTION

Note: *Manufactured by Evox-Rifa, Inc.

5.1 Calculate Integrating Capacitor (CINT)

The integrating capacitor must be selected to maximize integrator output voltage swing. The integrator output voltage swing is defined as the absolute value of V_{DD} (or V_{SS}) less 0.9V (i.e., V_{DD} – 0.9VI or V_{SS} +0.9VI). Using the 20µA buffer maximum output current, the value of the integrating capacitor is calculated using the following equation.

EQUATION 5-2: (T_{INT}) (20 x 10 ⁻⁶) (V_S - 0.9) $C_{INT} = \frac{(11N1)(20 \times 10^{-19})}{(11.8N)^{2}} \mu F$ where: T_{INT} = Integration Period $V_S = IV_{DD}$ C_{INT} = Integrated Capacitor Value (μ F).

It is critical that the integrating capacitor have a very low dielectric absorption. PPS capacitors are an example of one such dielectric. Table 5-2 summarizes various capacitors suitable for C_{INT} .

TABLE 5-2: RECOMMENDED CAPACITOR FOR CINT

Note: *Manufactured by Evox-Rifa, Inc.

5.2 Calculate V_{REF}

The reference de-integration voltage is calculated using the following equaton:

EQUATION 5-3:

5.3 Serial Port

Communication with the TC530/TC534 is accomplished over a 3 wire serial port. Data is clocked into D_{IN} on the rising edge of D_{CLK} and clocked out of D_{OUT} on the falling edge of D_{CLK} . R/W must be HIGH to read converted data from the serial port and LOW to write the LOAD VALUE to the TC530/TC534.

5.4 Data Read Cycle

Data is shifted out of the serial port in the following order: End of Conversion (EOC), Overrange (OVR), Polarity (POL), conversion data (MSB first). When R/W is high, the state of the $\overline{\text{EOC}}$ bit can be polled by simply reading the state of D_{OUT} . This allows the processor to determine if new data is available without connecting an additional wire to the EOC output pin (this is especially useful in a polled environment). See Figure 5-1.

5.5 Load Value Write Cycle

Following the power-up reset pulse, the LOAD VALUE (which sets the duration of AZ and INT) must next be transmitted to the serial port. To accomplish this, the processor monitors the state of EOC (which is available as a hardware output or at D_{OUT}). R/W is taken low to initiate the write cycle only when EOC is low (during the AZ phase). (Failure to observe EOC low may cause an offset voltage to be developed across C_{INT} , resulting in erroneous readings). The 8-bit LOAD VALUE data on D_{IN} is clocked in by D_{CLK} . The processor then terminates the write cycle by taking R/\overline{W} high. (Data is transferred from the serial input shift register to the time base counter on the rising edge of R/\overline{W} and data conversion is initiated). See Figure 5-2.

5.6 Input Multiplexer (TC534 Only)

A 4-input, differential multiplexer is included in the TC534. The states of channel address lines A0 and A1 determine which differential V_{1N} pair is routed to the converter input. A0 is the least significant address bit (i.e., channel 1 is selected when $A0 = 0$ and $A1 = 0$). The multiplexer is designed to be operated in a differential mode. For single-ended inputs, the CHx- input for the channel under selection must be connected to the ground reference associated with the input signal.

FIGURE 5-2: TC530/TC534 INITIALIZATION AND LOAD VALUE WRITE CYCLE

5.7 DC/DC Converter

An on-board, TC7660H-type charge pump supplies negative bias to the converter circuitry, as well as to external devices. The charge pump develops a negative output voltage by moving charge from the power supply to the reservoir capacitor at V_{SS} by way of the commutating capacitor connected to the CAP+ and CAP- inputs.

The charge pump clock operates at a typical frequency of 100kHz. If lower quiescent current is desired, the charge pump clock can be slowed by connecting an external capacitor from the OSC pin to V_{DD} . Reference typical characteristics curves.

6.0 TYPICAL CHARACTERISTICS

The graphs and tables following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs or tables, the data presented may be outside the specified operating range (e.g., outside specified power supply range), and therefore outside the warranted range.

7.0 PACKAGING INFORMATION

7.1 Package Marking Information

Package marking data not available at this time.

7.2 Taping Forms

7.3 Package Dimensions (Continued)

SALES AND SUPPORT

Data Sheets

Products supported by a preliminary Data Sheet may have an errata sheet describing minor operational differences and recommended workarounds. To determine if an errata sheet exists for a particular device, please contact one of the following:

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TC530/534

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